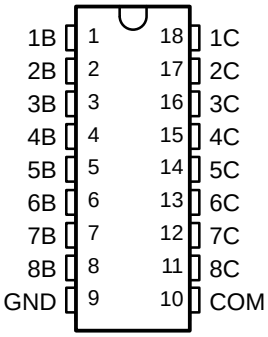
- **500 mA Rated Collector Current (Single Output)**
- **High-Voltage Outputs . . . 50 V**
- **Output Clamp Diodes**
- **Inputs Compatible With Various Types of Logic**
- **Relay Driver Applications**
- **Compatible with ULN2800A Series**

N PACKAGE
(TOP VIEW)



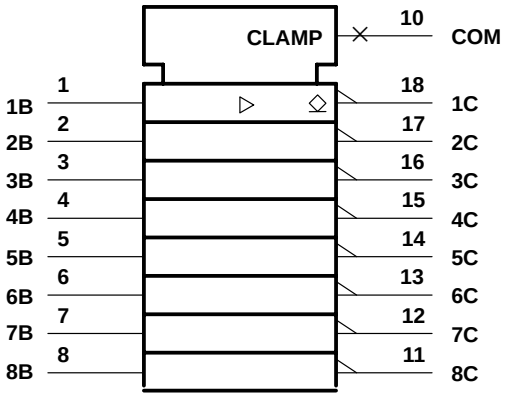
description

The ULN2803A is a monolithic high-voltage, high-current Darlington transistor array. The device consists of eight npn Darlington pairs that feature high-voltage outputs with common-cathode clamp diodes for switching inductive loads. The collector-current rating of each Darlington pair is 500 mA. The Darlington pairs may be paralleled for higher current capability.

Applications include relay drivers, hammer drivers, lamp drivers, display drivers (LED and gas discharge), line drivers, and logic buffers. The ULN2803A has a 2.7-kΩ series base resistor for each Darlington pair for operation directly with TTL or 5-V CMOS devices.

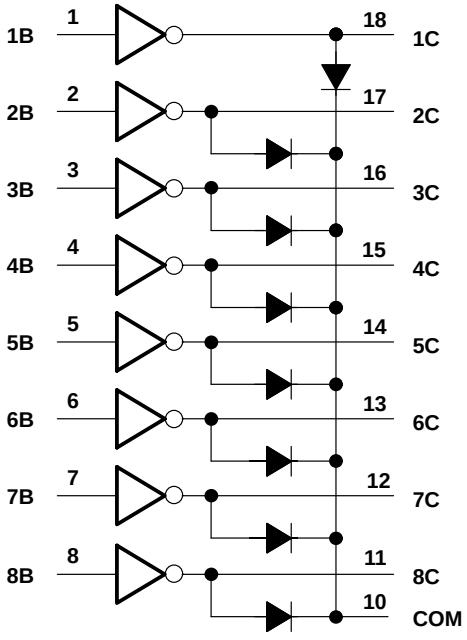
The ULN2803A is offered in a standard 18-pin dual in-line (N) package. The device is characterized for operation over the temperature range of –20°C to 85°C.

logic symbol†



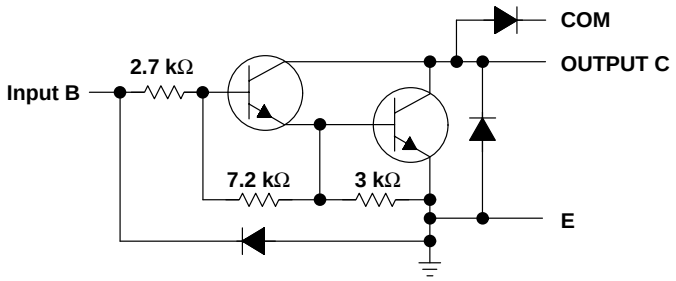
† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

schematic (each Darlington pair)



absolute maximum ratings at 25°C free-air temperature (unless otherwise noted)†

Collector-emitter voltage	50 V
Input voltage (see Note 1)	30 V
Continuous collector current	500 mA
Output clamp diode current	500 mA
Total substrate-terminal current	–2.5 A
Continuous dissipation at (or below) 25°C free-air temperature	1150 mW
Operating free-air temperature range, T_A	–20°C to 85°C
Storage temperature range, T_{stg}	–65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds:	260°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltages values, unless otherwise noted, are with respect to the emitter/substrate terminal GND.

electrical characteristics at 25°C free-air temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
I_{CEX}	Collector cutoff current	V_{CE} = 50 V, See Figure 1	I_I = 0,			50	μA
$I_{I(off)}$	Off-state input current	V_{CE} = 50 V, T_A = 70°C,	I_C = 500 μA, See Figure 2	50	65		μA
$I_{I(on)}$	Input current	V_I = 3.85 V,	See Figure 3		0.93	1.35	mA
$V_{I(on)}$	On-state input voltage	V_{CE} = 2 V, See Figure 4	I_C = 200 mA			2.4	V
			I_C = 250 mA			2.7	
			I_C = 300 mA			3	
$V_{CE(sat)}$	Collector emitter saturation voltage	I_I = 250 μA, See Figure 5	I_C = 100 mA,		0.9	1.1	V
		I_I = 350 μA, See Figure 5	I_C = 200 mA,		1	1.3	
		I_I = 500 μA, See Figure 5	I_C = 350 mA,		1.3	1.6	
I_R	Clamp diode reverse current	V_R = 50 V,	See Figure 6			50	μA
V_F	Clamp diode forward voltage	I_F = 350 mA,	See Figure 7		1.7	2	V
C_i	Input capacitance	V_I = 0 V,	f = 1 MHz		15	25	pF

switching characteristics at 25°C free-air temperature

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
t_{PLH}	Propagation delay time, low-to-high-level output	V_S = 50 V, C_L = 15 pF,	R_L = 163 Ω, See Figure 8		130		ns
t_{PHL}	Propagation delay time, high-to-low level output				20		
V_{OH}	High-level output voltage after switching	V_S = 50 V, See Figure 9	I_O ≈ 300 mA,	V_S–20			mV

PARAMETER MEASUREMENT INFORMATION

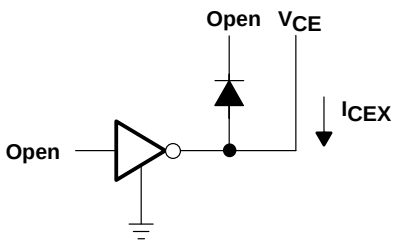


Figure 1. I_{CEX} Test Circuit

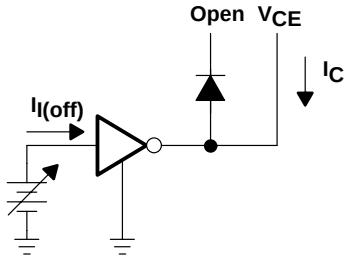


Figure 2. $I_{I(off)}$ Test Circuit

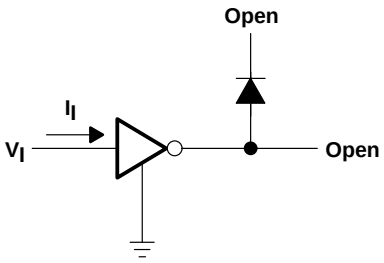


Figure 3. $I_{I(on)}$ Test Circuit

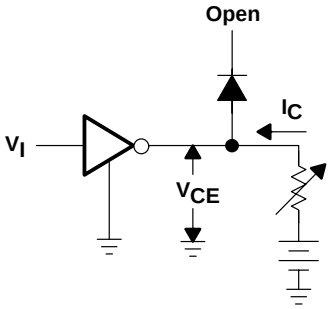


Figure 4. $V_{I(on)}$ Test Circuit

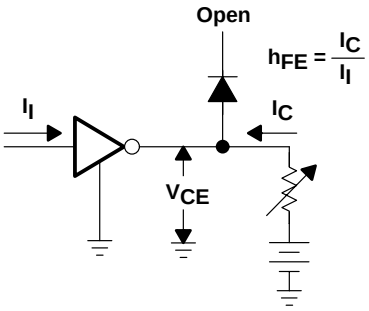


Figure 5. h_{FE}, $V_{CE(sat)}$ Test Circuit

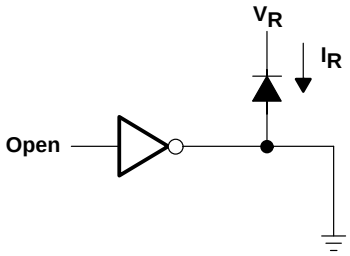


Figure 6. I_R Test Circuit

PARAMETER MEASUREMENT INFORMATION

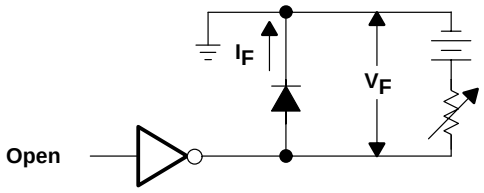
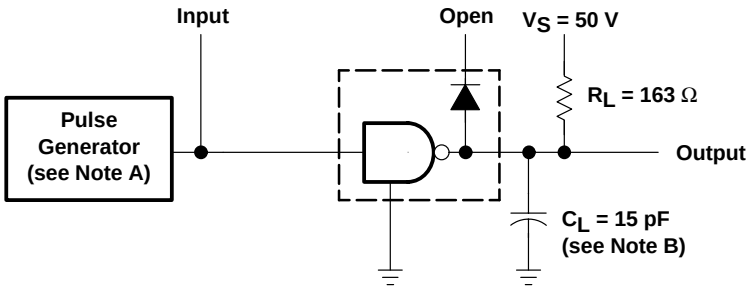
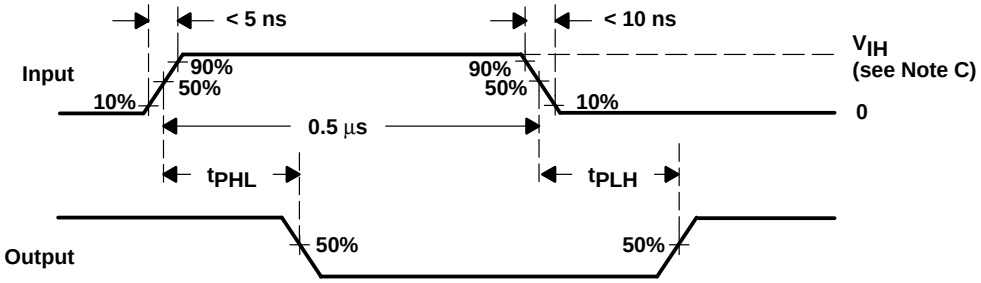


Figure 7. V_F Test Circuit



Test Circuit

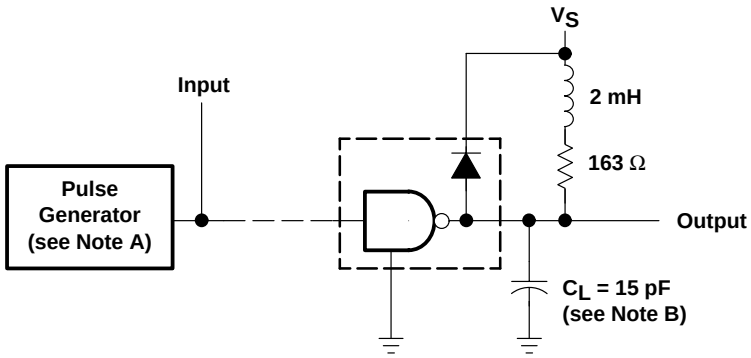


Voltage Waveforms

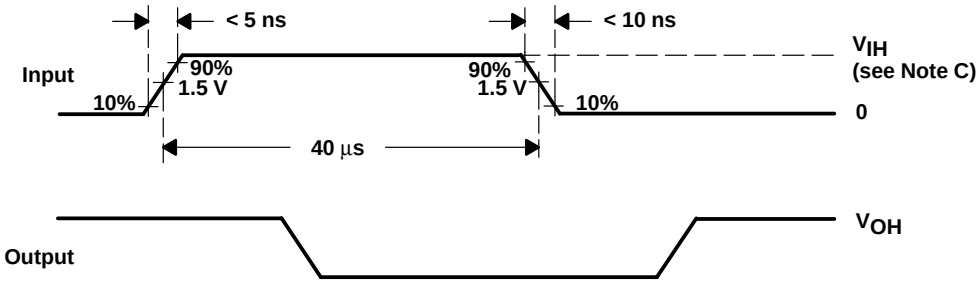
NOTES: A. The pulse generator has the following characteristics: PRR = 1 MHz, Z_O = 50 Ω.
B. C_L includes probe and jig capacitance.
C. V_{IH} = 3 V

Figure 8. Propagation Delay Times

PARAMETER MEASUREMENT INFORMATION



Test Circuit



Voltage Waveforms

NOTES: A. The pulse generator has the following characteristics: PRR = 12.5 KHz, Z_O = 50 Ω.
B. C_L includes probe and jig capacitance.
C. V_{IH} = 3 V

Figure 9. Latch-Up Test

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